Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,108	SHU ET AL.	
Examiner	Art Unit	
Emeka Ebirim	2166	

	SEAR	CHED	
Class	Subclass	Date	Examiner
707	1-10, 100	5/23/2006	EE
709	202	5/23/2006	EE

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEAR (INCLUDING S	CH NOTES EARCH STRATEGY	<u>()</u>
	DATE	EXMR
EAST search	5/23/2006	EE
Google scholar	5/23/2006	EE
ACM	5/23/2006	EE